PATENT

Attorney Docket No.: SAM-0210

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Serial No.: Chang-Whan Jung, et al.

09/879,637

Filing Date:

June 12, 2001

Title:

FUSE CIRCUIT FOR SEMICONDUCTOR INTEGRATED CIRCUIT

## CERTIFICATE OF FACSIMILE TRANSMISSION

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Examiner: Nguyen, Minh

Group Art Unit: 2816

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Commissioner for Patents

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The following is in response to the Office Action dated April 7, 2003 and is filed within the shortened statutory period of three months. Please amend the application as follows.

In the specification:

Please amend the abstract of the invention as follows.

(Twice Amended) In a fuse circuit including programmable fuses in a semiconductor integrated circuit, the fuses store specific information related to the semiconductor integrated circuit, such as redundancy information, wafer lot number, die lot number, and die position on the wafer, etc. The fuse circuit utilizes a plurality of fuses for storing identical bit information. Consequently, in the case where a fuse has not been cut out correctly, the fuse circuit can reduce programming defects, whereby defect generation rates are remarkably decreased.

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